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Wright

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(54) **METHOD AND AN APPARATUS TO DETECT LOW VOLTAGE**

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This patent is subject to a terminal disclaimer.

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(52) **U.S. Cl.** **324/713; 320/124; 320/127**

(58) **Field of Classification Search** **324/713; 320/127, 124**

See application file for complete search history.

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(57) **ABSTRACT**

A method and an apparatus to detect low voltage have been disclosed. One embodiment of the apparatus includes a main circuit powered at a supply voltage, wherein the supply voltage changes over time and a test circuit coupled to the main circuit, the test circuit being representative of a voltage sensitivity of the main circuit to dynamically determine if the supply voltage is above a minimum voltage at which the main circuit operates correctly, wherein the minimum voltage changes over at least one of a temperature and a time and between different instances of the main circuit.

23 Claims, 10 Drawing Sheets

